Search Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,565	NIE ET AL.
Examiner	Art Unit
Anthony Weier	1761

SEARCHED				
Class	Subclass	Date	Examiner	
426	656, 634	11/10/2006	AW	
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
DATE	EXMR		
11/10/2006	AW		
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